

**J**ournal of  
**I**ntegrated  
**C**ircuits and  
**S**ystems

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*Volume 7 • Number 2 • September 2012 • ISSN 1807-1953*

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Mauricio Oka

Michelly de Souza

Salvador Pinillos Gimenez

Siegfried Selberherr

Valeryia Kilchytska

Victor Sonnenberg

## CONTENTS

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Foreword .....85

### Special Section on Best SBMicro2011 Papers

Induced Optical Losses in Optoelectronic Devices due Focused  
Ion Beam Damages  
*F. Vallini, L. A. M. Barea, E. F. dos Reis, A. A. von Zuben and  
N. C. Frateschi* .....87

Modeling of Thin-Film Lateral SOI PIN Diodes with an Alternative  
Multi-Branch Explicit Current Model  
*D. Lugo-Muñoz, J. Muci, A. Ortiz-Conde, F. J. García-Sánchez,  
M. de Souza, D. Flandre, and M. A. Pavanello* .....92

A Simple Electron Mobility Model Considering the Silicon-Dielectric  
Interface Orientation for Circular Surrounding-Gate Transistor  
*A. L. Perin, A. S. N. Pereira, P. G. D. Agopian, J.A. Martino,  
and R. Giacomini* .....100

SOI n- and pMuGFET devices with different TiN metal gate thickness  
and crystallographic orientation of the sidewalls  
*M. Rodrigues, M. Galeti, N. Collaert, E. Simoen, C. Claeys,  
and J. A. Martino* .....107

One Transistor Floating Body RAM Performances on UTBOX  
Devices Using the BJT Effect  
*L.M.Almeida, K.R.A.Sasaki, M.Aoulaiche, E.Simoen, C.Claeys,  
and J.A.Martino* .....113

Impact of the Series Resistance in the I-V Characteristics of Junctionless  
Nanowire Transistors and its dependence on the Temperature  
*R. T. Doria, R. D. Trevisoli, M. de Souza, and M. A. Pavanello* .....121

### Regular Papers

Relative-Air Humidity Sensing Element Based on Heat Transfer of a  
Single Micromachined Floating Polysilicon Resistor  
*P. Zambrozi Jr. and F. Fruett* .....130

Fin Cross-Section Shape Influence on Short Channel  
Effects of MuGFETs  
*R. T. Bühler, R. Giacomini, M. A. Pavanello, and J. A. Martino* .....137

## FOREWORD

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This issue of the Journal of Integrated Circuits and Systems (JICS) features a very broad content, including papers on multiple gate devices, sensors and silicon photodiodes.

Six of these papers have been selected from the presentations given at SBMicro2011 (26th Symposium on Microelectronics Technology and Devices), which has been held in João Pessoa, Brazil in 2011. Among the contributions presented at Symposium, only a few best rated were selected by the JICS Editorial Board and have been invited to submit an extended version to the Journal. These papers have been reviewed by external experts and have been accepted for the special section on best SBMicro2011 papers. In addition to the best papers presented at the conference, spontaneous submissions passed through the usual reviewing process and have been accepted as regular papers.

We would like to thank the authors for their effort in preparing these high quality papers, as well as the reviewers for their help on paper selection, which guarantees the scientific level of this issue. We sincerely hope that JICS readers will enjoy these contributions.

Marcelo Lubaszewski  
*JICS Editor-in-chief*

Marcelo Antonio Pavanello  
*JICS Co-Editor*